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Power Inverter / Motor Driver Design for Reduced Emissions

Todd Hubing

Michelin Professor of Vehicular Electronics Clemson University



What is a Power Inverter?





Primary Sources of EMI from Power Inverters

- Conversion of differential-mode power currents to common-mode noise currents (imbalance)
- Electric field coupling from heatsinks
- EMI from digital electronic controls



Example of a Power Inverter Layout





Six-Step Inversion Waveforms





Common-Mode Currents



Phase Voltage A_{-to-circuit GND} (pink), Phase Voltage A_{-to-GND} (sky), Current Clamp probe voltage (yellow) and Phase Current A (Green)



Common Mode "Antenna" Currents





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Typical CM Current (Frequency Domain)





Typical Layout







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Common-Mode Current Due to Imbalance



Common-mode current from power converters and motor drivers is a common source of electromagnetic interference in automotive systems.

And yet, at their most basic level, these devices are inherently balanced.



Common-Mode Current Due to Imbalance



Imbalance arises from:

- geometrical asymmetries
- unequal turn-on and turn-off times
- unbalanced PWM control
- unbalanced filtering
- switching device parasitics
- imbalances in load impedance



Imbalanced vs. Balanced Design



Imbalance arises from:

- geometrical asymmetries unnecessary
- unequal turn-on and turn-off times can compensate
- unbalanced PWM control can use balanced method
- unbalanced filtering unnecessary
- switching device parasitics can compensate
- imbalances in load impedance can compensate



One Approach: A Balanced Cable Interface



If the source and cable are balanced, but the load is imbalanced, the imbalance in the load can be "hidden" from the rest of the system with a balancing network.



A Balanced Cable Interface (Balancing Network)



In our application (a motor driver), the source and load only need to appear balanced at radiated emission frequencies (particularly 30 – 80 MHz).



Test Set-up





A Balanced Cable Interface (Balancing Network)

Measured common-mode current with and without the balancing network





A Balanced Cable Interface (Balancing Network)

 $CMRR(I_{DM}/I_{CM}, I_{DM}=(I_1+I_2)/2)$ 40 Measured 35 common-mode both grounded(initial) 30 rejection ratio load-side balancing network load-balancing & source-unbalancing with and both balancing 25 both unbalancing without the S21(dB) 05 balancing network 15 10 5 0 10⁵ 10⁷ 10⁶ 10⁸ Frequency(Hz)







Measured common-mode current with (green) and without (black) the balancing network















Balanced cables



Unbalanced cables





How balanced

do the cables

need to be?

Summary 51 Ω Load side balancing network 100 Ω 50 Ω 50 Ω 100 Ω 50 Ω 100 Ω 100

- A balancing network can significantly reduce the common-mode currents on a balanced cable connected to an unbalanced load and/or source.
- These networks are relatively inexpensive to implement and can be more effective than common-mode chokes or ferrites.
- Although they are similar to standard filters, they are different in function and design. They reduce common-mode currents much more than differential-mode currents.



CM Current Due to Coupling from Heatsinks



Electric field coupling from heatsinks creates common-mode current on attached cables



Maximum Radiated Emissions Calculation



References

[1] H. Shim and T. Hubing, "Model for Estimating Radiated Emissions from a Printed Circuit Board with Attached Cables Driven by Voltage-Driven Sources," IEEE Transactions on Electromagnetic Compatibility, vol. 47, no. 4, Nov. 2005, pp. 899-907.

[2] Shaowei Deng, Todd Hubing, and Daryl Beetner, "Estimating Maximum Radiated Emissions From Printed Circuit Boards With an Attached Cable," IEEE Trans. on Electromagnetic Compatibility, vol. 50, no. 1, Feb. 2008, pp. 215-218.



Maximum Radiated Emissions Calculation









CM current is split among various cables (i.e. more cables doesn't result in more CM current).



Heatsink

Design Recommendations

- Pay close attention to all sources of imbalance.
- Put a chassis ground on board and incorporate a balancing network for medium to high power inverters.
- Keep voltage on heatsinks low relative to reference ground.
- Apply standard (good) EMC board design and layout practices for digital controls. (discussed in next presentation)



Grounding & Shielding in Mixed Signal PCBs

Todd H. Hubing

Clemson Vehicular Electronics Laboratory Clemson University



Recommendations

- Don't rely on EMC Design Guidelines
- Be familiar with currents and current paths
- Learn to recognize good EMI sources
- Learn to recognize good antennas
- Be aware of fundamental EMI radiation mechanisms
Signal Routing and Termination



Identify Current Paths



Current takes the path of least impedance!

> 100 kHz this is generally the path of least inductance< 10 kHz this is generally the path(s) of least resistance

Current Paths in traces that pass between plane pairs







Control transition times of digital signals!



Control transition times of digital signals!

Can use a series resistor or ferrite when load is capacitive.

Use appropriate logic for fast signals with matched loads.

Signal Termination

Reducing risetime with a series resistor

Reducing risetime with a parallel capacitor



Good idea



Bad idea

Signal Termination

Eliminating ringing with a series resistor

- Electrically small circuits
- Generally caused by too much inductance



Eliminating ringing due to mismatched transmission lines

- □ Electrically long circuits (length > risetime * velocity)
- □ Must match characteristic impedance at load or source end



When is a trace or cable a transmission line?



Steady state solution is always the wire-pair solution

- If we don't care about how we get to the steady state, then we don't need to worry about transmission line solutions.
- In many applications, we don't care!

When Routing Controlled Impedance Traces

When routing a trace between layers, route on either side of the same return plane.



When routing a trace between 2 different planes, use a transfer via near the signal via.



Identifying the Unintentional Antennas on a **Circuit Board**



Identifying Antennas



Identifying Antennas

| Good Antenna Parts | | Poor Antenna Parts | |
|--------------------|-------------------------------------|--|--------------------------------------|
| <100 MHz | >100 MHz | <100 MHz | >100 MHz |
| Cables | Heatsinks | Microstrip or stripline traces Anything that is not big | Microstrip or stripline traces |
| | Power planes | | |
| | Tall components | | |
| | Seams in shielding enclosures | | |

Free-space wavelength at 100 MHz is 3 meters

Noise Sources and Coupling Mechanisms



Identifying Sources (Diagnostics)

Clocks Narrow band, consistent

Digital Data Not as narrow as clocks, but clock frequency is usually identifiable.

Analog Bandwidth determined by signal source, signals consistent

PowerAppears broadband, but harmonics ofsupply switchingswitching frequency can be identified,
consistent

Arcing Broadband, intermittent

Parasitic oscillations Narrowband, possibly intermittent

Identifying Sources

Noise on the low-speed I/O



For some ICs, significant high-frequency currents appear on low-speed I/O including outputs that never change state during normal operation!

Noise can be coupled from a source to an antenna by one or more of three different coupling mechanisms:

Conducted

Electric field coupled

Magnetic field coupled

For printed circuit board analysis and design, it is convenient to express these coupling mechanisms in terms of voltage and current.

Voltage Driven

Signal or component voltage appears between two good antenna parts.

Example:



 $V_s = 1 \text{ volt } @ 500 \text{ MHz}$ $E_{rad} \approx 360 \text{ mV} / \text{m} @ 3 \text{ meters}$

More than 60 dB above the FCC Class B limit!

Current Driven

Signal current loop induces a voltage between two good antenna parts.



Direct coupling to I/O

Signals coupled to I/O lines carry HF power off the board.



Grounding for Mixed Signal PCBs



Lateral Isolation





Often the source of significant problems

Vertical Isolation



Only one plane usually needs to be full size.

One or zero vias should connect planes with different labels.

Why do I need more than one ground?

Where does each ground need to be?

How do I connect the grounds?

The purpose of a system ground is to provide a reference voltage and/or a safe path for fault currents.

Signal currents flowing on a "ground" conductor can prevent a ground conductor from serving its intended purpose.

Don't confuse ground conductors with signal return conductors. Rules for the routing of "ground" may conflict with the rules for routing signal or power returns.







Single-Point Ground



These are grounding strategies, not signal return strategies!

Important Concept

Current Driven Radiation Mechanism

Signal current loop induces a voltage between two good antenna parts.



How Much Isolation Can We Tolerate?





Why?

Conductors referenced to different grounds can be good antennas.

Signals referenced to two different grounds will be noisy (i.e. include the noise voltage between the two grounds).

Layouts with more than one ground are more difficult, require more space and present more opportunities for critical mistakes.

Excuses for employing more than one ground are generally based on inaccurate or out-dated information.

If grounds are divided, it is generally to control the flow of low-frequency (<100 kHz) currents.

For example,

Isolating battery negative (i.e. chassis ground) from digital ground

Isolating digital ground from analog ground in audio circuits.

This can be necessary at times to prevent common impedance coupling between circuits with low-frequency high-current signals and other sensitive electronic circuits.



Exercise: Trace the path of the digital and analog return currents.



Exercise: Trace the path of the digital and analog return currents.



Exercise: Trace the path of the digital and analog return currents.



Design Exercise: What is wrong with this design and how would you improve it?


Ground vs. Signal Return

You don't need to gap a plane to control the flow of high frequency (>1MHz) currents. If you provide a low-inductance path for these currents to take, they will confine themselves to this path very well.

Ground vs. Signal Return

Rules for gapping a ground plane:

- 1. Don't do it!
- 2. If you must do it, never ever allow a trace or another plane to cross over the gap.
- 3. If you must do it, never ever place a gap between two connectors.
- 4. Remember that the conductors on either side of the gap are at different potentials.
- 5. See Rule #1!

Mixed-Signal Designs

If you have analog and digital returns that must be isolated (to prevent common-impedance coupling):

Route the returns on separate conductors

- Provide a DC connection at the one point (or in the one area) where the reference potential must be the same.
- This must include every place where a trace crosses the boundary between the analog and digital regions.

Mixed-Signal Designs

Example: How would you modify this design?



Mixed-Signal Designs

Example: A much better design





[†]Schottky diodes only needed for short circuit protection when V_{CC} > 15 V. See SHORT CIRCUIT PROTECTION section in Application Information.

September 23, 2010

Figure 35. Stereo Class/D/With Single-Ended Inputs

Sensitive A/D Isolation



If you think you need two vias, then you shouldn't be isolating the analog and digital grounds.

Provide a good HF chassis ground at connector

Cables and enclosures are both good antenna parts. If they are not held to the same potential, they are likely to create a radiation problem.

Exceptions:

- When there is no chassis ground
- When there are no connectors with cables

Note: Sometimes low-frequency isolation between chassis and digital ground is necessary control the flow of low-frequency currents. However, even in these situations it is usually important to provide a good high-frequency connection.

Isolating Chassis and Digital Grounds



Capacitors from I/O to Chassis

Caps with traces





Better implementation

Design Example



⁻ Connection to power plane

-O Connection to ground plane

Design Example



- Connection to power plane
- -O Connection to ground plane

Key Points

- Identify your HF ground and be sure it is the only ground that is large or connected to anything large!
- Don't call anything other current carrying nets "ground". For example, refer to a current carrying analog reference net as "analog return".
- Be aware of where your HF and LF currents are flowing!
- Isolate returns only when necessary to control the flow of low frequency currents.
- If you isolate two large conductors at low frequencies, be sure they are well connected at high frequencies.

Filtering

Two capacitors more than twice as good as one.



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Electric Field

Shielding

+V-

 \Rightarrow

(a.)

(b.)

(C.)

- V+

Magnetic Field Shielding

(at high frequencies)



Magnetic Field Shielding

(at low frequencies)







(b.)

Enclosure Shielding



DC Power Distribution and Decoupling



Power Bus Decoupling Strategy

With closely spaced (<.25 mm) planes

- size bulk decoupling to meet board requirements
- size local decoupling to meet board requirements
- mount local decoupling in most convenient locations
- don't put traces on capacitor pads
- too much capacitance is ok
- too much inductance is not ok

References:

T. H. Hubing, J. L. Drewniak, T. P. Van Doren, and D. Hockanson, "Power Bus Decoupling on Multilayer Printed Circuit Boards," *IEEE Transactions on Electromagnetic Compatibility*, vol. EMC-37, no. 2, May 1995, pp. 155-166.

T. Zeeff and T. Hubing, "Reducing power bus impedance at resonance with lossy components," IEEE Transactions on Advanced Packaging, vol. 25, no. 2, May 2002, pp. 307-310.

M. Xu, T. Hubing, J. Chen, T. Van Doren, J. Drewniak and R. DuBroff, "Power bus decoupling with embedded capacitance in printed circuit board design," IEEE Transactions on Electromagnetic Compatibility, vol. 45, no. 1, Feb. 2003, pp. 22-30.

Power Bus Decoupling Strategy

With widely spaced (>.5 mm) planes

- size bulk decoupling to meet board requirements
- size local decoupling to meet device requirements
- mount local decoupling near pin connected to furthest plane
- don't put traces on capacitor pads
- too much capacitance is ok
- too much inductance is not ok

References:

J. Chen, M. Xu, T. Hubing, J. Drewniak, T. Van Doren, and R. DuBroff, "Experimental evaluation of power bus decoupling on a 4-layer printed circuit board," *Proc. of the 2000 IEEE International Symposium on Electromagnetic Compatibility*, Washington D.C., August 2000, pp. 335-338.

T. H. Hubing, T. P. Van Doren, F. Sha, J. L. Drewniak, and M. Wilhelm, "An Experimental Investigation of 4-Layer Printed Circuit Board Decoupling," *Proceedings of the 1995 IEEE International Symposium on Electromagnetic Compatibility*, Atlanta, GA, August 1995, pp. 308-312.

J. Fan, J. Drewniak, J. Knighten, N. Smith, A. Orlandi, T. Van Doren, T. Hubing and R. DuBroff, "Quantifying SMT Decoupling Capacitor Placement in DC Power-Bus Design for Multilayer PCBs," IEEE Transactions on Electromagnetic Compatibility, vol. EMC-43, no. 4, Nov. 2001, pp. 588-599.

Power Bus Decoupling Strategy

With no power plane

- Iayout low-inductance power distribution
- size bulk decoupling to meet board requirements
- size local decoupling to meet device requirements
- two caps can be much better than one
- avoid resonances by minimizing L

References:

T. Hubing, "Printed Circuit Board Power Bus Decoupling," *LG Journal of Production Engineering*, vol. 3, no. 12, December 2000, pp. 17-20. (Korean language publication).

T. Zeeff, T. Hubing, T. Van Doren and D. Pommerenke, "Analysis of simple two-capacitor low-pass filters," IEEE Transactions on Electromagnetic Compatibility, vol. 45, no. 4, Nov. 2003, pp. 595-601.

Design Summary

- Early EMC design is important
- Don't rely on design guidelines!
- Pay attention to current paths!
- Pay attention to transition times!
- Recognize antennas!
- Recognize sources!
- Don't gap digital ground planes!



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Component-Level Characterization for System-Level Emissions Simulations

Todd Hubing

Michelin Professor of Vehicular Electronics Clemson University



Full-Wave EM Modeling of Real Systems



Requires a little intelligent simplification!





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Full-Wave EM Modeling of Real Systems





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- IEC 61967-1 General conditions and definitions
- IEC 61967-2 Measurement of radiated emissions TEM cell method
- IEC 61967-3 Measurement of radiated emissions surface scan method
- IEC 61967-4 Measurement of electromagnetic emissions 1Ω/150Ω direct coupling
- IEC 61967-5 Measurement of electromagnetic emissions workbench Faraday cage method
- IEC 61967-6 Measurement of electromagnetic emissions magnetic probe method



- IEC 61967-1 General conditions and definitions
- IEC 61967-2 Measurement of radiated emissions TEM cell method
- □ IEC 61967-3 Measurement of radiated emissions surface scan method near fields
- IEC 61967-4 Measurement of electromagnetic emissions $1\Omega/150\Omega$ direct coupling conducted
- IEC 61967-5 Measurement of electromagnetic emissions workbench Faraday cage method who knows what
- IEC 61967-6 Measurement of electromagnetic emissions magnetic probe method



Component measurements should characterize the source in order to build models that can be used at the system level.

Otherwise, they are not particularly useful for system-level modeling!



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Measurements must be:

- Meaningful
- Repeatable
- Targeted



Standards SAE J1752/3 and IEC 61967-2





Energy must be coupled from an IC before it can be radiated

- Integrated circuits (ICs) are generally the ultimate source of unintentional electromagnetic emissions from electronic devices and systems.
- However, ICs are too small to radiate significantly themselves.
- In order to radiate fields strong enough to cause an interference problem, energy must be coupled from the IC package to larger structures that act as antennas such as circuit board planes, heatsinks or cables.



Energy must be coupled from an IC before it can be radiated

There are only three ways that energy can be coupled from an IC to surrounding structures:

Conducted on two or more pins;

- Electric field coupled;
- Magnetic field coupled.



Electric Field Coupling to the Septum of a Mini-TEM Cell

Electric field coupling can be represented with a mutual capacitance, C_{TEM} . The voltage coupled to either end of the TEM cell will be identical.





Magnetic Field Coupling to the Septum of a Mini-TEM Cell

Magnetic field coupling can be represented with a mutual inductance, M_{TEM} . Voltage appears across both terminations with opposite phase.




Separating Coupling Mechanisms using a Hybrid Coupler

- A hybrid can be used to differentiate electric and magnetic field coupling.
- The A-B output indicates the amount of magnetic field coupling.
- The A+B output indicates the amount of electric field coupling.





Mini-TEM Cell





Electric Field Coupling







Voltage-Driven Radiation Mechanism

If we know C_{trace} and V_{DM} , we can calculate maximum possible radiated emissions due to electric field coupling!





Correlating Ctrace to C_{TEM}

A TEM cell measurement gives us the product of C_{trace} and V_{DM} , which is sufficient to calculate maximum possible radiated emissions due to electric field coupling!



 $C_{trace} \approx C_{TEM} / 2.1$

S. Deng, et. al., "Characterizing the Electric-Field Coupling from IC-Heatsink Structures to External Cables using TEM-Cell Measurements," *IEEE Trans. on Electromagnetic Compatibility*, vol. 49, no. 4, Nov. 2007, pp. 785-791.



Hybrid TEM Cell Electric Field Coupling





Calculation of Emissions Based on a TEM Cell Measurement





Magnetic Field Emissions

Current-Driven Common-Mode (Magnetic-Field) Coupling



Source can be fully characterized by the current I_{DM} and the mutual inductance (source loop to antenna loop).



Magnetic Field Emissions

A TEM cell measurement gives us the value of V_{CM} , which is sufficient to calculate maximum possible radiated emissions due to magnetic field coupling!



S. Deng, et. al., "Using TEM Cell Measurements to Estimate the Maximum Radiation from PCBs with Attached Cables due to Magnetic Field Coupling," *IEEE Transactions on Electromagnetic Compatibility*, May 2008.



Hybrid TEM Cell Magnetic Field Coupling





Using Mini-TEM Cell Measurement Results

- By connecting both outputs of the TEM cell to a hybrid, it is possible to separate the electric field coupling from the magnetic field coupling.
- Magnetic-Field coupling is fully characterized by the source current and mutual inductance to the radiating structure. These are both determined by the TEM cell measurement.
- Electric-Field coupling is fully characterized by the source voltage and the capacitance of the device being driven to infinity. These can both be determined by the TEM cell measurement.
- Therefore, a TEM cell measurement can be used to extract the parameters required to predict maximum radiated emissions due to coupling from an electrically small source.



Conducted Coupling





Conducted Coupling



Existing methods for measuring conducted emissions are limited by parasitics, however it is often possible to make meaningful measurements up to GHz frequencies.

- V_{open} is approximately equal to the voltage measured across a 150 Ω load if connection parasitics are controlled.
- I_{short_max} is approximately equal to the current delivered to a 1 Ω load if connection parasitics are controlled.
- Internal capacitances can be modeled explicitly if known or implicitly included in the value of V(f)



Measurement Test Set-Up





Model vs. Measurement





Maximum Emissions Estimate





Conducted Coupling Source Model





IEC 61967-4 Test Configuration



helpful for selecting an IC, but the procedure has significant limitations and does not fully characterize the IC output drivers.



Conducted Coupling





Thevenin Equivalent Circuit and V-I Curve





Limitation Of IEC 61967-4



Known source V_{oc} : 10V, R_{th} : 50 Ω

Sensitive to Measurement error
Sensitive to the assumed V_{oc}
Sensitive to the ωL ,|Z_{th}|





Conducted Coupling

There are **3** unknowns: V(f), R(f) and |X(f)| requiring **3** measurements to characterize the source.



- V_{open} is approximately equal to the voltage measured across a 500-Ω load if connection parasitics are controlled.
- I_{short_max} is approximately equal to the current delivered to a 1-Ω load if connection parasitics are controlled.

Additional measurement across a 50-Ω load gives us the 3 data points required to characterize the source.



Three load conditions for characterizing conducted EMI sources



$$\begin{aligned} \left| V_{50\Omega_Load} \right| &= \left| V_{th} \right| \left| \frac{50\Omega}{50\Omega + Z_{th}} \right| \\ \left| V_{short_Load} \right| &= \left| V_{th} \right| \left| \frac{R_{short}}{R_{short} + Z_{th}} \right| \\ \left| V_{open_Load} \right| &= \left| V_{th} \right| \left| \frac{R_{open}}{R_{open} + Z_{th}} \right| \\ Z_{th} &= R_{th} + jX_{th} \\ R_{short} &= 1\Omega \parallel 50\Omega, R_{open} = 500\Omega \end{aligned}$$



Conducted EMI Measurement Conclusions

- Open and short circuit measurements are usually best approximated by 1-ohm and 500-ohm measurements on real devices
- Small measurement errors can result in large model errors.
- A 1/50/500 ohm measurement reduces the susceptibility of the test the measurement errors.
- Reactive source impedances require multiple complex loads to characterize accurately.



Direct Radiation from Component



At GHz frequencies, ICs with large heatsinks can radiate directly

These measurements can be made by mounting the board on the floor of a semi-anechoic chamber.



Summary

- Measurements of an integrated circuit in a hybrid TEM cell configuration can be used to obtain values for the "electric moment" and "magnetic moment" associated with an IC as it is configured on a given circuit board.
- Direct radiation can be measured in a semi-anechoic chamber, but component should be mounted in the floor to eliminate unwanted reflections and prevent currents on cables and other objects from contributing to the measurement.
- A 1/50/500 ohm conducted emissions measurement (as opposed to the current 1/150 ohm measurement) is capable of determining the value of Rmin, which is critical for system-level modeling.



Summary

- ICs with smaller moments are less likely to couple to other parts of a system resulting in unintentional radiated emissions.
- Electric and magnetic moments can be used in full-wave electromagnetic models of a system, replacing complex ICpackage geometries with simple equivalent sources.
- A similar procedure involving a hybrid TEM cell could be used to determine these "moments" for larger structures (e.g. automotive components) at lower frequencies.



How EMC Engineers Use Electromagnetic Modeling Tools

Todd H. Hubing

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Modeling Software

Fasthenry NEC Fastcap **SuperNEC** GEMACS Quickfield VISU Δ **SUPERFISH** FLO/EMC **EMC Workbench** Accufield MaxSIM-F MagNet **Microwave Explorer Fastlap** ANCE **Maxwell 3D** Ε ΔΡ **MSC EMAS** Flux3D **ContecRADIA** COMOIF3 HFSS APOGEE MiniNEC FM



The HYPE



a

The REALITY

CVEL

THE CLEMSON UNIVERSITY VEHICULAR ELECTRONICS LABORATORY

Simple Geometries Modeled with Popular Electromagnetic Modeling Codes



Even simple geometries are difficult to model using most commercial tools.

Software attempts to model configurations that it can't model.

Geometries analyzed are not always the what the user is led to believe.

Users must understand EM theory.

Users must be familiar with the limitations of the particular technique.

Users must be familiar with the peculiarities of the software and its user interface.



EMC Analysis Software

Analytical Modeling Software

specific geometries, closed-form equations limited scope, maximum convenience

Numerical Modeling Software

solves Maxwell's equations, accurate solutions to well-defined problems limited scope, requires expert user

Design Rule Checkers

review designs for rule violations that may result in problems very limited scope, maximum convenience

Expert System / Maximum Emissions Calculators

review designs for specific problem sources identify areas requiring a more careful evaluation estimate maximum possible emissions



EM Modeling Software

Circuit and Transmission Line Solvers

- 2D and 3D Static Field Solvers
- 2D and "2.5 D" HF Field Solvers
- 3D HF (Full-Wave) Field Solvers



Circuit Solvers

Every EMC Engineer should have access to a basic SPICE-like circuit solver.

Help's engineers to intuitively understand how intentional and unintentional currents propagate.

For lumped-element modeling of signal paths and coupling paths.

- For time-domain modeling of RLC equivalent circuits.
- For modeling non-linear behavior of components and circuits.



Lumped-Element Modeling







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Modeling Time-Domain RLC Circuits

Circuit Board Nets




Modeling Non-Linear Behavior



- Transient protection
- Ferrites near saturation
- □ IC inputs near saturation



Transmission Line Modeling















Static Electric-Field Solvers

A 2D or 3D static field solver is often the most useful computer modeling tool in an EMC Engineer's tool kit.

Help's engineers to visualize electric fields

- This is an essential skill for EMC engineers and HF board designers.
- Calculating "balance factor"
- Evaluating effectiveness of electric-field shields
- Estimating mutual capacitance of structures



Electric Field Coupling/Shielding







Guard Trace Effect







Guard Trace vs. Guard Stack





Orientation of Daughter Card





Grounding of Heatsink





Effectiveness of Electric Field Shields





Calculating Mutual Capacitance





Calculating Imbalance Factor



T. Watanabe, O. Wada, T. Miyashita, and R. Koga, "Common-Mode-Current Generation Caused by Difference of Unbalance of Transmission Lines on a Printed Circuit Board with Narrow Ground Pattern," IEICE Trans. Commun. vol. E83-B, no. 3, Mar. 2000.



Calculating Imbalance Factor

For microstrip trace structures, the imbalance parameter is given by,

$$h = \frac{C_{trace}}{C_{trace} + C_{board}}$$

where C_{trace} and C_{board} are the stray capacitances per unit length of the signal trace and the ground plane, respectively.

T. Watanabe, H. Fujihara, O. Wada, Y. Toyota, R. Koga, and Y. Kami, "A prediction method of common-mode excitation on a printed circuit board having a signal trace near the ground edge," *IEICE Trans. Commun.* vol. E87-B, no. 8, Aug. 2004.



Example: Using balance factor to calculate emissions



Unintended coupling to an I/O line.



Example: Using balance factor to calculate emissions



(c)





Example: Using balance factor to calculate emissions



Equivalent antenna model.



2-D and "2.5-D" High-Frequency Field Solvers

High-Frequency field solvers are generally not capable of modeling static fields, but 2-D and 2.5-D tools have several advantages when compared to 3D Full-Wave field solvers.

Generally, they ...

- Are **much** more efficient (i.e. faster and/or model more detail)
- Have a more intuitive user interface
- Less prone to numerical errors



2-D and "2.5-D" High-Frequency Field Solvers

Examples of 2-D and 2.5-D HF field solvers:

- 2D tools for modeling axi-symmetric 3D configurations
- 2D tools for modeling PCB cross-sections
- □ 2.5-D tools for modeling PCB traces in layered media



3-D full wave modeling codes are useful for:

- Learning about EM wave propagation
- Understanding how different structures can act as antennas
- Modeling the behavior of circuit components and packages
- Developing and validating other types of models
- □ Validating measurements of well defined source configurations



3-D full wave modeling codes are NOT useful for:

- Evaluating existing product designs
- Predicting EMC problems
- Troubleshooting EMC problems
- Validating EMI measurements of electronic devices



Understanding how different structures can act as antennas





Finding resonant frequencies of structures





Validating Maximum Radiated Emissions Calculations





Low-Cost CEM Tools

Free Software:

- FEMM
- Ansoft Maxwell SV
- EMAP
- Students' QuickField
- Antenna Model
- LC
- MEEP
- OpenFMM
- pdnMesh
- Radia
- ToyFDTD
- Scatlab

\$2k - \$10k:

- EZ-EMC
- EZNEC Pro
- GEMACS
- Tricomp-Estat
- Trace Analyzer



CEM Tools (more than \$10k)

- AMDS
- □ All IES codes (Ampere ...)
- Analyst
- ApsimFDTD-SPICE
- AXIEM
- CableMod/PCBMod
- Compliance
- Comsol Multiphysics
- CRIPTE
- CST Microwave Studio
- EMA3D
- EMC Studio
- EMDS
- Maxwell
- MFlex
- emGine Environment
- EMPIRE Xccel
- **G** Fidelity
- FEKO



- GEMS
- HFSS
- HFWorks
- 🗆 IE3D
- JCMSuite
- OptEM Cable Designer
- OptEM Inspector
- Magnet
- Microwave Office
- Momentum
- PAM-CEM
- Q3D Extractor
- SEMCAD X
- Sonnet
- WIPL-D Pro
- Xenos
- XFDTD
- C XGtd

Key Point

Computer models often yield incorrect results because:

- Software was not capable of analyzing the input configuration
- Software defaults were inappropriate for the problem
- The input was not exactly what the user thought
- Results were misinterpreted by the user



Summary

- Numerical EM modeling tools require the user to be familiar with EM theory, the limitations of the techniques being applied, and the limitations of the particular software implementation.
- Numerical EM modeling tools should only be trusted when the solutions can be confirmed by other methods.
- Numerical EM modeling tools are NOT particularly useful for the design and troubleshooting of digital electronics products.



Design Rule Checkers



Scan a board layout looking for design rule violations.

- Advantages Easier to understand what the software is doing Easier to use.
- Disadvantages Design rules don't apply in all situations Higher board cost to meet unnecessary design rules Will not detect problems that don't violate a pre-defined rule



EMC Design Guideline Collection

http://www.cvel.clemson.edu/emc/

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What is a PCB EMC Expert System?

EMC Expert System software should work with automated printed circuit board layout tools to:

review and analyze printed circuit board designs;

point out problems with the layout;

- estimate levels of radiated EMI;
- anticipate ESD and radiated susceptibility problems; and
- provide circuit and board layout design advice.

Using the same general approach that human experts would use.







Radiation Mechanisms

Differential-Mode Radiation

- from electrically small structures
- from resonant structures

Coupling to I/O Radiation

- crosstalk on circuit board
- · near-field coupling to connector

Voltage-Driven Common-Mode Radiation

- from cables (coupled from traces or heatsinks)
- from shielded enclosures

Current-Driven Common-Mode Radiation

- from cables
- from shielded enclosures

Power Bus Radiation

- · directly from power bus
- coupled to shielded enclosure



Expert System Algorithms are constantly asking the question,



What is the worst that could happen?



Effect of Extended Cable on Ground







Algorithms Locate Hard-to-Find Problems





Algorithms Locate Hard-to-Find Problems





Algorithms Locate Hard-to-Find Problems



View of left half of board showing the problem nets.


Algorithms Locate Hard-to-Find Problems

Type of Problem I Identified





Algorithms Locate Hard-to-Find Problems

Current-Driven Common-Mode Problem.





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Algorithms Locate Hard-to-Find Problems





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Maximum Radiated EMissions Calculator





Maximum Radiated Emissions Calculator

| 🍘 Maximum Emission Calculator: Voltage-Driven CM EMI Algorithm - Internet Explorer | | | | | | | | | | |
|---|------|---|----------------------|---------------------|----------------------|--|--|--|--|--|
| 🚱 🔾 👻 http://www.clemson.edu/cvel/modeling/EMAG/MaxEMCalculator/MREMC-example.html 🔹 🐓 🗙 Google 🖉 🖉 | | | | | | | | | | |
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Voltage-Driven Common-Mode EMI Calculator

The electric fields that couple directly to attached cables from a trace can induce common-mode currents on these cables resulting in radiated emissions. This source mechanism is referred to as voltage-driven, since the magnitude of the common-mode current is proportional to the signal voltage and independent of the signal current. For a given board geometry, a closed-form expression for the maximum emissions due to this coupling mechanism was developed in [1,2]. The number of cables attached to the board and the location of these cables does not affect the maximum emissions calculation.

Assumptions:

- The board is not within a shielding enclosure. (There's a different calculator for this case.)
- There is at least one cable attached to the board and the cable length is much greater than the board dimensions.

| Return plane | \sim | | Voltage Source | | | Ē |
|--|---------------------------------|---|---|-----------------|------------------|-----------------|
| | + at | | Oigital Signal - Trapezoidal Waveform | | | 25 |
| | W | | Amplitude of the signal (A): | 3.3 | V | 25 |
| Geometry: | | | Rise time (t_p) : | 5 | ns | |
| | inches | | Fall time (t_f) : | 5 | ns | |
| | e millimete | rs | Duty Cycle: | 50 | % | |
| Board length (L): | 50 | mm | Data Rate: | 5 | Mbps | 20 |
| Board width (W): | 50 | mm | | | | 10 ¹ |
| Trace length (l_t) : | 10 | mm | Swept Frequency - Constant Volta | ge | | |
| Trace height over the return plane (h_t) : | 1 | mm | Amplitude of the voltage signal (A): | | V | |
| Trace width (a_t) : | 2.2 | mm | Lower frequency (f_0) : | | MHz | |
| Measurement distance (r): | 3 | meters | Upper frequency (f ₁): | | MHz | |
| | | | | Calcu | Ilate Now | |
| References | | | | | | |
| [1] Hwan Woo Shim, "Development of of Missouri-Rolla, 2004. | 'Radiated EM | I Estimation A | Algorithms for PCB EMI Expert System," PA | n.D Dissertatio | n, University | |
| [2] Shaowei Deng, Todd Hubing, and Attached Cable," IEEE Trans. on Elect | l Daryl Beetne tromagnetic (| er, " <u>Estimating</u> Compatibility, | Maximum Radiated Emissions From Printe vol. 50, no. 1, Feb. 2008, pp. 215-218. | ed Circuit Boa | ards With an | |
| | | | | | | http://www.clem |
| | | | Internet Protected N | 1ode: On | 100 ⁶ | • |



http://www.clemson.edu/cvel/modeling



Computer Modeling Tools for EMC Engineers

- Rule Checkers For analyzing existing system designs.
- Emissions Calculators/ Expert Systems
- Numerical Modeling Tools

For understanding basic field behavior in well defined situations.





For More Information:

http://www.cvel.clemson.edu/modeling



- List of "free" EM modeling codes.
- List of commercial EM modeling codes.
- Info on EM modeling techniques.
- Info on EM modeling software.
- Prototype MR EMC calculator.

